PATENT COOPERATION TREATOBLON, SPIVAK, McCLELLAND

DOCKETING DEPT.

rom the NTERNATIONAL PRELIMINARY MINING AUTHORITY	Init Date Docketed: (A) Tyle Resp(s):
To: GREGORY J. MAIER OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT P.C. 1940 DUKE STREET ALEXANDRIA, VIRGINIA 22314	EXAMINATION REPORT
,	

OF

(PCT Rule 71.1)

Date of Mailing (day/month/year)	2 (3 ()(

Applicant's or agent's file reference IMPORTANT NOTIFICATION Priority date (day/month/year) 220148 WO International filing date (day/month/year) International application No. 19 September 2002 (19.09.2002) 22 September 2003 (22.09.2003) PCT/US03/26302 Applicant TOKYO ELECTRON LIMITED

- The applicant is hereby notified that this International Preliminary Examining Authority transmits herewith the international preliminary examination report and its annexes, if any, established on the international application.
- 2. A copy of the report and its annexes, if any, is being transmitted to the International Bureau for communication to all the elected Offices.
- Where required by any of the elected Offices, the International Bureau will prepare an English translation of the report (but not of any annexes) and will transmit such translation to those Offices.

REMINDER

The applicant must enter the national phase before each elected Office by performing certain acts (filing translations and paying national fees) within 30 months from the priority date (or later in some Offices)(Article 39(1))(see also the reminder sent by the International Bureau with Form PCT/IB/301).

Where a translation of the international application must be furnished to an elected Office, that translation must contain a translation of any annexes to the international preliminary examination report. It is the applicant's responsibility to prepare and furnish such translation directly to each elected Office concerned.

For further details on the applicable time limits and requirements of the elected Offices, see Volume II of the PCT Applicant's Guide.

Name and mailing address of the IPEA/US

Mail Stop PCT, Attn: IPEA/US Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450 Authorized officer

Luz L. Alejandro

Telephone No. 703-308-0661

Facsimile No. (703) 305-3230 Form PCT/IPEA/416 (July 1992)

ternational application No.	
CT/US03/26302	
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T.	Basis of the report	
1	With regard to the elements of	f the international application:*
•	the international appl	ication as originally filed.
	the description:	1
		as originally filed
	pages NONE	
	pages NONE	, filed with the retter of
	the claims:	The filed
		, as originally filed , as amended (together with any statement) under Article 19
1	pages NONE	, filed with the letter of
	the drawings:	
1		, as originally filed
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İ	pages NONE	, filed with the letter of
Ì	the sequence listing	part of the description:
	pages NONE	, as originally filed
	pages NONE	, filed with the demand , filed with the letter of
	language in which the in	ternational application was filed, unless otherwise indicated under this item.
	TIL alamonto MOTO 3V	ilable or nimished to this Authority in the re-
	the language of a tr	ranslation furnished for the purposes of international search (under Rule23.1(b)).
1	the language of pu	olication of the international application (under Rule 48.3(b)).
	the language of the	translation furnished for the purposes of international preliminary examination(under Rules
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	3. With regard to any nuc	eotide and/or amino acid sequence disclosed in the international application, the examination was carried out on the basis of the sequence listing:
	contained in the in	ternational application in printed form.
	filed together with	the international application in computer readable form.
١	furnished subsequ	ently to this Authority in written form.
١	Cinhad gubangu	ently to this Authority in computer readable form.
-	The statement that	the subsequently furnished written sequence listing does not go beyond the disclosure in the
	international appli	cation as filed has been furnished.
	The statement tha	the information recorded in computer readable form is identical to the written sequence listing
	has been furnishe	
	4. The amendments	have resulted in the cancellation of:
•	the descri	otion, pages NONE
	· ==	, Nos. NONE
	the drawin	ngs sheets/fig NONE
	la mi	e crablished as if (some of) the amendments had not been made, since they have been considered to go
	beyond the disclosi	are as filed, as indicated in the Supplemental Box (Rule 70.2(0)).
	* Replacement sheets which	tre as filed, as indicated in the supplemental box (state) have been furnished to the receiving Office in response to an invitation under Article 14 are referred to in d" and are not annexed to this report since they do not contain amendments (Rules 70.16 and 70.17). Intaining such amendments must be referred to under item 1 and annexed to this report.
	Any replacement sheet co	

International application No. PCT/US03/26302

v.	Reasoned statement under R 56.2(a)(ii) wit citations and explanations supporting such sta	ith regard to novelty, inventive standard industrial applicability;	
1.	STATEMENT Novelty (N)	Claims 5-7,16-20,25-27,29-31 and 33 YE Claims 1-4, 8-15, 21-24, 28, 32 NC	
	Inventive Step (IS)	Claims NONE YE Claims 1-33 NO	
	Industrial Applicability (IA)	Claims 1-33 YI Claims NONE NO	ES O

2. CITATIONS AND EXPLANATIONS Please See Continuation Sheet

Form PCT/IPEA/409 (Box V) (July 1998)

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(To be used when the space in any of the preceding boxes is not sufficient)

Claims 1-4, 8-15, 21-24, 28 and 32 lack novelty under PCT Article 33(2) as being anticipated by Koshimizu, U.S. Patent 5,290,383. Koshimizu shows the invention as claimed including process chamber comprising a viewing port coupled to the process chamber, wherein the viewing port comprises: a viewing window to permit optical access to the process chamber; a mounting to couple the viewing window to the process chamber; and a viewing window cleaning apparatus, comprising a RF source and an inductive coil as a plasma source, coupled to the mounting and disposed between the viewing window and the process chamber, and configured to form a cleaning plasma in a cleaning plasma region of the mounting; wherein the viewing window cleaning apparatus further comprises an impedance match assembly and a plasma generator; a gas injection system is coupled to the cleaning plasma region; and wherein the supporting section of the viewing window is configured to position the viewing window at a predetermined position relative to a position of the process chamber. For a complete description of the apparatus see fig. 26 and its description.

With respect to claims 9-14, note that the cleaning plasma etches by-products deposited on the viewing window through physical/chemical etching. Furthermore, the claims are directed to method limitations instead of apparatus limitations and since an apparatus is being claimed as the instant invention to method teachings are not considered to be the matter at hand, since a variety of methods can be done with the apparatus. The method limitations are viewed as intended uses which do not further limit, and therefore, do not patentably distinguish the claimed invention.

Regarding claims 28 and 32, Koshimizu discloses the claimed method of cleaning a viewing window for a process chamber.

Claims 5-7, 18-20, 25-27 and 29 lack an inventive step under PCT Article 33(3) as being obvious over Koshimizu, U.S. Patent 5,290,383 in view of Masuda et al., U.S. Patent 6,503,364 or Masuda et al., JP 2001-77092A.

Koshimizu is applied as above but does not expressly discloses an apparatus further comprising at least one array of magnets coupled to the mounting. Masuda et al. (both '364 and '092) discloses an apparatus comprising a viewing window having a mounting couple to it and further comprising an array of magnets for suppressing adhesion of deposits onto the window (see, for example, figs. 1-3 and their description, especially col. 8, lines 13-33). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the apparatus of Koshimizu by further comprising an array of magnets in order to suppress adhesion of deposits in the window.

Claims 17 and 30 lack an inventive step under PCT Article 33(3) as being obvious over Koshimizu, U.S. Patent 5,290,383 in view of Chen et al., U.S. Patent 6,071,375 or Melvin et al., U.S. Patent 6,306,246.

Koshimizu is applied as above but does not expressly disclose wherein the gas injection system is configured to flow a gas into the cleaning plasma region so that a pressure is generated in the cleaning plasma region, the pressure substantially opposing a propagating direction of by-products. Chen et al. discloses an apparatus in which a gas injection system is configured to flow a gas into the a cleaning plasma region, around a viewing window, so that a pressure is generated in the cleaning plasma region, the pressure substantially opposing a propagating direction of by-products in order to avoid the accumulation of by-products particulates or other contaminants (see, for example, figs. 1-3, and col. 3-line 19 to col. 5-line 60). Additionally, Melvin et al. discloses an

Form PCT/IPEA/409 (Continuation Sheet) (July 1998)

International application No. PCT/US03/26302



Supplemental Box

(To be used when the space in any of the preceding boxes is not sufficient)

apparatus in which a gas injection system is configured to flow a gas into the a cleaning plasma region, around a viewing window, so apparatus in winen a gas injection system is comigured to now a gas into the a cleaning plasma region, about a viewing window, so that a pressure is generated in the cleaning plasma region, the pressure substantially opposing a propagating direction of by-products that a pressure is generated in the creating prasma region, the pressure substantiarry opposing a propagating direction of by products particulates or other contaminants (see, for example, figs. 2-4, and their in order to avoid the accumulation of by-products particulates or other contaminants (see, for example, figs. 2-4, and their in order to avoid the accumulation of by products paraculates of other comandations (see, for complet, right, and their descriptions). Therefore, in view of these disclosures, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the apparatus of Koshimizu as to comprise the a gas injection system configured to flow a gas into the cleaning plasma region so that a pressure is generated in the cleaning plasma region, the pressure substantially opposing a propagating direction of by-products in order to avoid the accumulation of by-products particulates or other contaminants.

Claims 16, 31 and 33 lack an inventive step under PCT Article 33(3) as being obvious over Koshimizu, U.S. Patent 5,290,383. Claims 16, 31 and 33 lack an inventive step under PCT Article 33(3) as being obvious over Koshimizu, U.S. Patent 5,290,383. Koshimizu is applied as above but does not expressly disclose that the predetermined position in which the viewing window is koshimizu to the position of the chamber is selected so that a substantial amount of by-products do not travel to the viewing positioned relative to the position of the chamber is selected so that a substantial amount of by-products do not travel to the viewing window. However, the it would have been an obvious choice of design to one of ordinary skill in the art to optimize the window. However, the it would have been an obvious choice of design to one of ordinary routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experimentation depending upon, for example, location/position of the viewing window relative to the process chamber during routine experi				
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